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8/10/12/14-Bit High Bandwidth Multiplying DACs with Serial Interface

Preliminary Technical Data AD5450/AD5451/AD5452/AD5453*

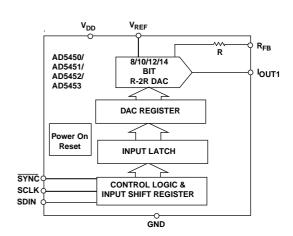
FEATURES

+2.5 V to +5.5 V Supply Operation 50MHz Serial Interface 10MHz Multiplying Bandwidth ±10V Reference Input 8-Lead TSOT & MSOP Packages Pin Compatible 8, 10, 12 and 14 Bit Current Output DACs Extended Temperature range -40°C to +125°C Guaranteed Monotonic Four Quadrant Multiplication Power On Reset with brown out detect <5μA typical Current Consumption

APPLICATIONS

Portable Battery Powered Applications Waveform Generators Analog Processing Instrumentation Applications Programmable Amplifiers and Attenuators Digitally-Controlled Calibration Programmable Filters and Oscillators Composite Video Ultrasound Gain, offset and Voltage Trimming

FUNCTIONAL BLOCK DIAGRAM



GENERAL DESCRIPTION

The AD5450/AD5451/AD5452/AD5453 are CMOS 8, 10, 12 and 14-bit Current Output digital-to-analog converters respectively.

These devices operate from a +2.5 V to 5.5 V power supply, making them suited to battery powered applications and many other applications.

These DACs utilize double buffered 3-wire serial interface that is compatible with SPI^{TM} , $QSPI^{TM}$, $MICROWIRE^{TM}$ and most DSP interface standards.

On power-up, the internal shift register and latches are filled with zeros and the DAC output is at zero scale.

As a result of manufacture on a CMOS sub micron process, they offer excellent four quadrant multiplication characteristics, with large signal multiplying bandwidths of 10MHz.

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The applied external reference input voltage (V_{REF}) determines the full scale output current. An integrated feedback resistor (R_{FB}) provides temperature tracking and full scale voltage output when combined with an external Current to Voltage precision amplifier.

The AD5450/AD5451/AD5452/AD5453 DACs are available in small 8-lead TSOT & MSOP packages.

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Parameter	Min	Тур	Max	Units	Conditions
STATIC PERFORMANCE					
AD5450					
Resolution			8	Bits	
Relative Accuracy			± 0.25	LSB	
Differential Nonlinearity			$\pm \frac{1}{2}$	LSB	Guaranteed Monotonic
AD5451					
Resolution			10	Bits	
Relative Accuracy			± 0.25	LSB	
Differential Nonlinearity			± 1/2	LSB	Guaranteed Monotonic
AD5452			1.0	D.4	
Resolution			12	Bits	
Relative Accuracy			± 0.5	LSB LSB	Currenteed Manatania
Differential Nonlinearity AD5453			± 1⁄2	LSD	Guaranteed Monotonic
Resolution			14	Dite	
			$\begin{array}{c} 14\\\pm2 \end{array}$	Bits LSB	
Relative Accuracy			± 2 ± 1	LSB	Guaranteed Monotonic
Differential Nonlinearity Total Unadjusted Error			$^{\pm 1}_{\pm 2.44}$	mV	Guaranteeu Monotonic
Gain Error			$\pm 2.44 \pm 1.22$	mV	
Gain Error Temp Coefficient ²		± 5	±1.22	ppm FSR/°C	
Output Leakage Current		± 3	±10	nA	Data = $0000_{\rm H}$, T _A = 25°C, I _{OUT1}
Output Leakage Cuttent			± 10 ± 50	nA	Data = $0000_{\rm H}$, $\Gamma_{\rm A} = 2.5$ C, $\Gamma_{\rm OUT1}$ Data = $0000_{\rm H}$, $\Gamma_{\rm OUT1}$
Output Voltage Compliance Range		1.23	± 30	V	$Data = 0000_{\rm H}, 1_{\rm OUT1}$
		1.20		v	
REFERENCE INPUT ²					
Reference Input Range		±10		V	
V _{REF} Input Resistance	8	9.3	12	kΩ	Input resistance TC = -50ppm/°C
DIGITAL INPUTS ²					
Input High Voltage, V _{IH}	2.0			V	$V_{DD} = 3.6 V$ to 5 V
	1.7			V	$V_{DD} = 2.5$ V to 3.6 V
Input Low Voltage, V _{IL}			0.8	V	$V_{DD} = 2.7 V$ to 5.5 V
			0.7	V	$V_{DD} = 2.5 V$ to 2.7 V
Input Leakage Current, I _{IL}			1	μA	
Input Capacitance			10	pF	
DYNAMIC PERFORMANCE ²					
Reference Multiplying BW		10		MHz	$V_{REF} = +/-3.5V$, DAC loaded all 1s
Output Voltage Settling Time		10			$V_{\text{REF}} = 10V$, $R_{\text{LOAD}} = 100\Omega$, $C_{\text{LOAD}} = 15\text{pF}$
Output voltage Setting Time					
		100			DAC latch alternately loaded with 0s and 1s.
AD5450		100		ns	Measured to +/-16mV of FS
AD5451		110		ns	Measured to +/-4mV of FS
AD5452		160		ns	Measured to +/-1mV of FS
AD5453		180		ns	Measured to +/-1mV of FS
Digital Delay		20	40	ns	Interface delay time
10% to 90% Dettling Time		10	30	ns	Rise and Fall time, $V_{REF} = 10V$, $R_{LOAD} =$
					100Ω , $C_{LOAD} = 15 pF$
Digital to Analog Glitch Impulse		3		nV-s	1 LSB change around Major Carry, $V_{REF}=0V$
Multiplying Feedthrough Error					DAC latch loaded with all 0s.
		-75		d B	Reference = 1 MHz.
					Reference = 10 MHz.
Output Capacitance		_			
IOUT1		5		pF	DAC Latches Loaded with all Os
		10		pF	DAC Latches Loaded with all 1s
IOUT2		10		pF	DAC Latches Loaded with all 0s
		5		pF	DAC Latches Loaded with all 1s
Digital Feedthrough		0.1		nV-s	Feedthrough to DAC output with CS high
	1				and Alternate Loading of all 0s and all 1s.

Parameter	Min	Тур	Max	Units	Conditions
Total Harmonic Distortion		-80		d B	$V_{REF} = 3.5$ V pk-pk, All 1s loaded, f = 1kHz
Digital THD, Clock = 1MHz					
50kHz f _{OUT}		75		d B	
Output Noise Spectral Density		25		nV/√Hz	@ 1kHz
SFDR performance (Wideband)					Update = 1 MHz, $V_{REF} = 3.5$ V
Update = 1MHz					-
50kHz Fout		78		d B	
20kHz Fout		78		d B	
SFDR performance (NarrowBand)					Update = 1 MHz, $V_{REF} = 3.5$ V
50kHz Fout		87		d B	-
20kHz Fout		87		d B	
Intermodulation Distortion		78		d B	f1 = 20kHz, f2 = 25kHz, Update=1MHz,
					$V_{REF}=3.5V$
POWER REQUIREMENTS					
Power Supply Range	2.5		5.5	V	
I _{DD}			1	μA	Logic Inputs = 0 V or V_{DD}
Power Supply Sensitivity ²			0.001	%/%	$\Delta V_{DD} = \pm 5\%$

 $(V_{DD} = 2.5 \text{ V to } 5.5 \text{ V}, V_{REF} = +10 \text{ V}, I_{OUT}x = 0 \text{ V}.$ All specifications T_{MIN} to T_{MAX} unless otherwise noted. DC performance measured with OP1177, AC performance with AD9631 unless otherwise noted.)

NOTES

¹Temperature range is as follows: Y Version: -40°C to +125°C.

²Guaranteed by design and characterisation, not subject to production test.

Specifications subject to change without notice.

TIMING CHARACTERISTICS¹ ($V_{REF} = +5 V$, $I_{0UT}2 = 0 V$. All specifications T_{MIN} to T_{MAX} unless otherwise noted.)

Parameter	$V_{DD} = 4.5 \text{ V to } 5.5 \text{ V}$	$V_{DD} = 2.5 V \text{ to } 5.5 V$	Units	Conditions/Comments
f _{SCLK}		50	MHz max	Max Clock frequency
t ₁		20	ns min	SCLK Cycle time
t ₂		8	ns min	SCLK High Time
t ₃		8	ns min	SCLK Low Time
t ₄		8	ns min	SYNC falling edge to SCLK active edge setup time
t ₅		5	ns min	Data Setup Time
t ₆		4.5	ns min	Data Hold Time
t ₇		5	ns min	SYNC rising edge to SCLK active edge
t ₈		30	ns min	Minimum SYNC high time

NOTES

¹See Figures 1. Temperature range is as follows: Y Version: -40° C to $+125^{\circ}$ C. Guaranteed by design and characterisation, not subject to production test. All input signals are specified with tr =tf = 5ns (10% to 90% of V_{DD}) and timed from a voltage level of (V_{IL} + V_{IH})/2.

Specifications subject to change without notice.

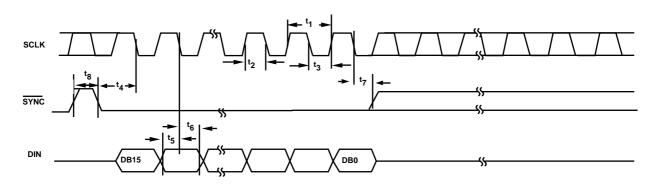


Figure 1. Timing Diagram.

ABSOLUTE MAXIMUM RATINGS^{1, 2}

$(T_A = +25^{\circ}C \text{ unless otherwise noted})$	
V _{DD} to GND	-0.3 V to +7 V
V _{REF} , R _{FB} to GND	-12 V to +12 V
I _{OUT} 1 to GND	–0.3 V to +7 V
Input Current to any pin except supplies	±10 mA
Logic Inputs & Output ³ -0.	$3V$ to V_{DD} +0.3 V
Operating Temperature Range	
Industrial (Y Version)	-40°C to +125°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature	+150°C
8 lead MSOP θ_{JA} Thermal Impedance	206°C/W
8 lead TSOT θ_{JA} Thermal Impedance	211°C/W
Lead Temperature, Soldering (10second	s) 300°C
IR Reflow, Peak Temperature (<20 seco	nds) +235°C

NOTES

¹Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

² Transient currents of up to 100mA will not cause SCR latchup.

³Overvoltages at SCLK, *SYNC*, DIN, will be clamped by internal diodes. Current should be limited to the maximum ratings given.

ORDERING GUIDE

Model	Resolution	INL	Temperature Range	Package Description	Branding	Package Option
AD5450YUJ	8	±0.25	-40 °C to +125 °C	TSOT		UJ-8
AD5451YUJ	10	±0.25	-40 °C to +125 °C	TSOT		UJ-8
AD5452YUJ	12	± 0.5	-40 °C to +125 °C	TSOT		UJ-8
AD5452YRM	12	± 0.5	-40 °C to +125 °C	MSOP		RM-8
AD5453YUJ	14	± 2	-40 °C to +125 °C	TSOT		UJ-8
AD5453YRM	14	± 2	-40 °C to +125 °C	MSOP		RM-8

CAUTION -

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD5450/AD5451/AD5452/AD5453 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



MSOP	тѕот	Mnemonic	Function
1	8	I _{OUT} 1	DAC Current Output.
2	7	GND	Ground Pin.
3	6	SCLK	Serial Clock Input. By default, data is clocked into the input shift register on the falling edge of the serial clock input. Alternatively, by means of the serial control bits, the device may be configured such that data is clocked into the shift register on the rising edge of SCLK.
4	5	SDIN	Serial Data Input. Data is clocked into the 16-bit input register on the active edge of the serial clock input. By default, on power up, data is clocked into the shift register on the falling edge of SCLK. The control bits allow the user to change the active edge to rising edge.
5	4	SYNC	Active Low Control Input. This is the frame synchronization signal for the input data. Data is loaded to the shift register on the active edge of the following clocks.
6	3	V _{DD}	Positive power supply input. These parts can operate from a supply of $+2.5$ V to $+5.5$ V.
7	2	V _{REF}	DAC reference voltage input pin.
8	1	R _{FB}	DAC feedback resistor pin. Establish voltage output for the DAC by connecting to external amplifier output.

PIN FUNCTION DESCRIPTION

PIN CONFIGURATION

TSOT (UJ-8)

RFB ● AD5450/ 8 IOUT1 VREF 2 AD5451/ 7 GND VDD 3 (Not to Scale) 6 SCLK SYNC 4 5 SDIN

MSOP (RM-8)

	•	8 RFB
GND 2	AD5452/ AD5453	7 VREF
SCLK 3	(Not to Scale)	6 V _{DD}
SDIN 4		5 SYNC

TERMINOLOGY

Relative Accuracy

Relative accuracy or endpoint nonlinearity is a measure of the maximum deviation from a straight line passing through the endpoints of the DAC transfer function. It is measured after adjusting for zero and full scale and is normally expressed in LSBs or as a percentage of full scale reading.

Differential Nonlinearity

Differential nonlinearity is the difference between the measured change and the ideal 1 LSB change between any two adjacent codes. A specified differential nonlinearity of -1 LSB max over the operating temperature range ensures monotonicity.

Gain Error

Gain error or full-scale error is a measure of the output error between an ideal DAC and the actual device output. For these DACs, ideal maximum output is V_{REF} – 1 LSB. Gain error of the DACs is adjustable to zero with external resistance.

Output Leakage Current

Output leakage current is current which flows in the DAC ladder switches when these are turned off. For the I_{OUT1} terminal, it can be measured by loading all 0s to the DAC and measuring the I_{OUT1} current. Minimum current will flow in the I_{OUT2} line when the DAC is loaded with all 1s

Output Capacitance

Capacitance from I_{OUT1} or I_{OUT2} to AGND.

Output Current Settling Time

This is the amount of time it takes for the output to settle to a specified level for a full scale input change. For these devices, it is specified with a 100 Ω resistor to ground. The settling time specification includes the digital delay from SYNC rising edge to the full scale output change.

Digital to Analog Glitch Impulse

The amount of charge injected from the digital inputs to the analog output when the inputs change state. This is normally specified as the area of the glitch in either pA-secs or nV-secs depending upon whether the glitch is measured as a current or voltage signal.

Digital Feedthrough

When the device is not selected, high frequency logic activity on the device digital inputs may be capacitively coupled through the device to show up as noise on the I_{OUT} pins and subsequently into the following circuitry. This noise is digital feedthrough.

Multiplying Feedthrough Error

This is the error due to capacitive feedthrough from the DAC reference input to the DAC I_{OUT1} terminal, when all 0s are loaded to the DAC.

Total Harmonic Distortion (THD)

The DAC is driven by an ac reference. The ratio of the rms sum of the harmonics of the DAC output to the fundamental value is the THD. Usually only the lower order harmonices are included, such as second to fifth.

$$THD = 20 \log \sqrt{(V_2^2 + V_3^2 + V_4^2 + V_5^2)}$$

 V_1

Digital Intermodulation Distortion

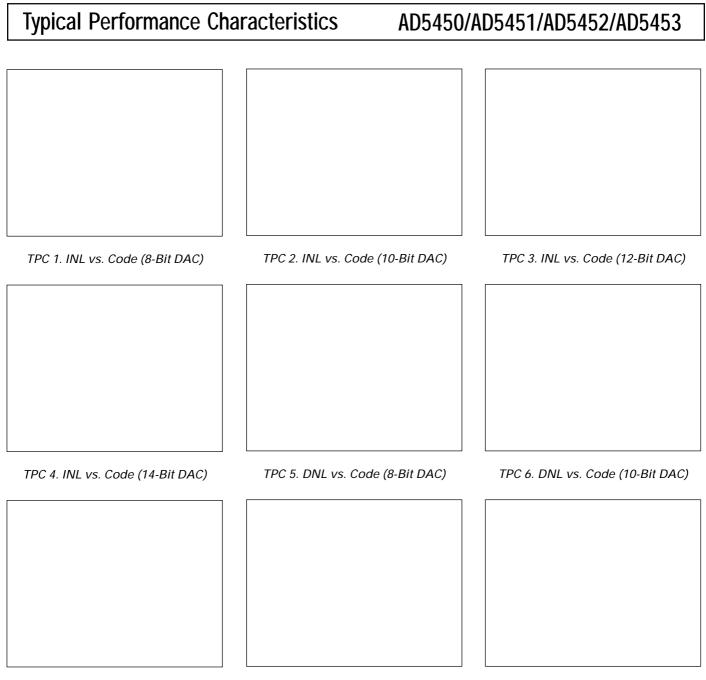
Second order intermodulation (IMD) measurements are the relative magnitudes of the fa and fb tones generated digitally by the DAC and the second order products at 2fa-fb and 2fb-fa.

Compliance Voltage Range

The maximum range of (output) terminal voltage for which the device will provide the specified characteristics.

Spurious-Free Dynamic Range(SFDR)

It is the usable dynamic range of a DAC before spurious noise interferes or distorts the fundamental signal. SFDR is the measure of difference in amplitude between the fundamental and the largest harmonically or nonharmonically related spur from dc to full Nyquist bandwidth (half the DAC sampling rate or fs/2). Narrow band SFDR is a measure of SFDR over an arbitrary window size, in this case 50% of hte fundamental. Digital SFDR is a measure of the usable dymanic range of the DAC when the signal is a digitally generated sine wave.



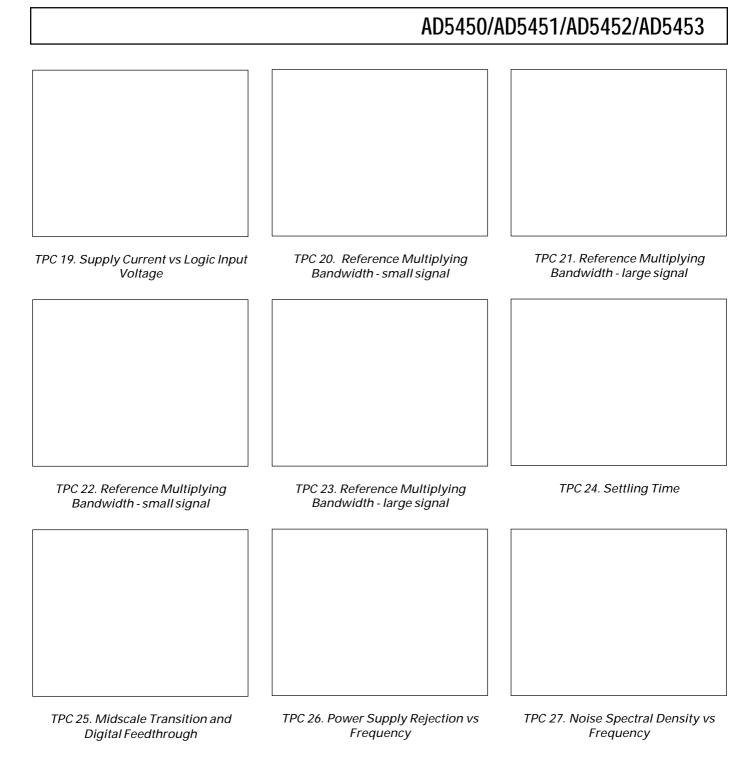
TPC 7. DNL vs. Code (12-Bit DAC)

TPC 8. DNL vs. Code (14-Bit DAC)

TPC 9. INL vs Reference Voltage

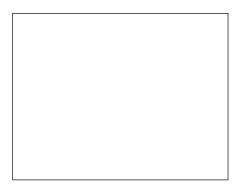
AD5450/AD5451/AD5452/AD5453



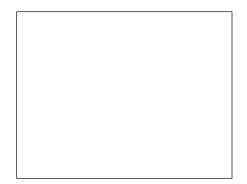


AD5450/AD5451/AD5452/AD5453

TPC 28. TBD



TPC 29. TBD



TPC 30. TBD

GENERAL DESCRIPTION DAC SECTION

The AD5450, AD5451, AD5452 and AD5453 are 8, 10, 12 and 14 bit current output DACs consisting of a segmented (4-Bits) inverting R-2R ladder configuration. The feedback resistor R_{FB} has a value of R. The value of R is typically $9.3k\Omega$ (minimum $8k\Omega$ and maximum $12k\Omega$). If I_{OUT1} is kept at the same potential as GND, a constant current flows in each ladder leg, regardless of digital input code. Therefore, the input resistance presented at V_{REF} is always constant and nominally of value R. The DAC output (I_{OUT}) is code-dependent, producing various resistances and capacitances. External amplifier choice should take into account the variation in impedance generated by the DAC on the amplifiers inverting input node.

Access is provided to the V_{REF} , R_{FB} , and I_{OUT1} terminals of the DAC, making the device extremely versatile and allowing it to be configured in several different operating modes, for example, to provide a unipolar output and in four quadrant multiplication in bipolar mode. Note that a matching switch is used in series with the internal R_{FB} feedback resistor. If users attempt to measure R_{FB} , power must be applied to V_{DD} to achieve continuity.

SERIAL INTERFACE

The AD5450/AD5451/AD5452/AD5453 have an easy to use 3-wire interface which is compatible with SPI/QSPI/ MicroWire and DSP interface standards. Data is written to the device in 16 bit words. This 16-bit word consists of 2 control bits and either 8, 10 12, or 14 data bits as shown in Figure 2. The AD5453 uses all 14 bits of DAC data. The AD5452 uses twelve bits and ignores the two LSBs,

AD5450/AD5451/AD5452/AD5453

similarly the AD5451 uses ten bits and ignores the four LSBs, while the AD5450 uses eight bits and ignores the last six bits.

DAC Control Bits C1, C0

Control bits C1 and C0 the user to load and update the new DAC code and to change the active clock edge. By default the shift register clocks data in on the falling edge, this can be changed via the control bits. In this case, the DAC core is inoperative until the next data frame. A power cycle resets this back to default condition. On chip power on reset circuitry ensures the device powers on with zeroscale loaded to the DAC register and I_{OUT} line.

TABLE III. DAC CONTROL BITS

C1 C0 Funtion Implemented

0 0 Load and Update(Power On Default)

0 1 Reserved 1 0 Reserved

1 1 Clock Data to shift register On Rising Edge

SYNC Function

SYNC is an edge-triggered input that acts as a frame synchronization signal and chip enable. Data can only be transferred into the device while SYNC is low. To start the serial data transfer, SYNC should be taken low observing the minimum SYNC falling to SCLK falling edge setup time, t_4 .

After the falling edge of the 16th SCLK pulse, bring SYNC high to transfer data from the input shift register to the DAC register.

DB15 ((MSB)	-	-	-										DB0	(LSB)
C1	C0	DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0	х	х	х	х	х	х
		-					— D.	АТА В	ITS –						-

Figure 2a. AD5450 8 bit Input Shift Register Contents

DB15 (MSB) DB0 (L: C1 C0 DB9 DB8 DB7 DB6 DB5 DB4 DB3 DB2 DB1 DB0 X X X												(LSB)			
C1	C0	DB9	DB8	DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0	х	х	х	х
-		•					— D	ATA B	ITS –						-
CONT	CONTROL BITS														

Figure 2b. AD5451 10 bit Input Shift Register Contents

DB15	(MSB))					_	_						DB0	(LSB)
C1	CO	DB11	DB10	DB9	DB8	DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0	х	х
-	->	-					— р	ATA B	ITS -						->
CONT	ROL E	ITS													

Figure 2c. AD5452 12 bit Input Shift Register Contents

DB15 (MSB) DE C1 C0 DB13 DB12 DB11 DB10 DB9 DB8 DB7 DB6 DB5 DB4 DB3 DB2 DB												DB0	(LSB)		
C1 (CO	DB13	DB12	DB11	DB10	DB9	DB8	DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0
							D	АТА В	ITS –						->

Figure 2c. AD5453 14 bit Input Shift Register Contents

CIRCUIT OPERATION

Unipolar Mode

Using a single op amp, these devices can easily be configured to provide 2 quadrant multiplying operation or a unipolar output voltage swing as shown in Figure 3.

When an output amplifier is connected in unipolar mode, the output voltage is given by:

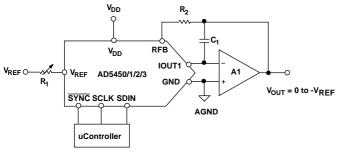
 $V_{OUT} = -D/2^n x V_{REF}$

Where D is the fractional representation of the digital word loaded to the DAC, and n is the number of bits.

D = 0 to 255 (8-Bit AD5450)

- = 0 to 1023 (10-Bit AD5451)
- = 0 to 4095 (12-Bit AD5452)
- = 0 to 16383 (14-Bit AD5453)

Note that the output voltage polarity is opposite to the V_{REF} polarity for dc reference voltages.



NOTES:

¹R1 AND R2 USED ONLY IF GAIN ADJUSTMENT IS REQUIRED. ²C1 PHASE COMPENSATION (1pF - 5pF) MAY BE REQUIRED IF A1 IS A HIGH SPEED AMPLIFIER.

Figure 3. Unipolar Operation

These DACs are designed to operate with either negative or positive reference voltages. The $V_{\rm DD}$ power pin is only used by the internal digital logic to drive the DAC switches' ON and OFF states.

These DACs are also designed to accommodate ac reference input signals in the range of -10V to +10V.

With a fixed 10 V reference, the circuit shown above will give an unipolar 0V to -10V output voltage swing. When $V_{\rm IN}$ is an ac signal, the circuit performs two-quadrant multiplication.

The following table shows the relationship between digital code and expected output voltage for unipolar operation. (AD5450, 8-Bit device).

Table	I.	Unipolar	Code	Table
-------	----	----------	------	-------

Digital Input	Analog Output (V)
1111 1111 1000 0000 0000 0001	$-V_{REF}$ (255/256) $-V_{REF}$ (128/256) = $-V_{REF}/2$ $-V_{REF}$ (1/256)
0000 0000	$-V_{\rm REF} (0/256) = 0$

Bipolar Operation

In some applications, it may be necessary to generate full 4-Quadrant multplying operation or a bipolar output swing. This can be easily accomplished by using another external amplifier and some external resistors as shown in Figure 4. In this circuit, the second amplifier A2 provides a gain of 2. Biasing the external amplifier with an offset from the reference voltage results in full 4-quadrant multiplying operation. The transfer function of this circuit shows that both negative and positive output voltages are created as the input data (D) is incremented from code zero ($V_{OUT} = -V_{REF}$) to midscale ($V_{OUT} - 0V$) to full scale ($V_{OUT} = +V_{REF}$).

$$V_{OUT} = (V_{REF} \times D / 2^{n-1}) \cdot V_{REF}$$

Where D is the fractional representation of the digital word loaded to the DAC and n is the resolution of the DAC.

D = 0 to 255 (8-Bit AD5450)

= 0 to 1023 (10-Bit AD5451)

= 0 to 4095 (12-Bit AD5452)

= 0 to 16383 (14-Bit AD5453)

When $V_{\rm IN}$ is an ac signal, the circuit performs four-quadrant multiplication.

Table II. shows the relationship between digital code and the expected output voltage for bipolar operation (AD5450, 8-Bit device).

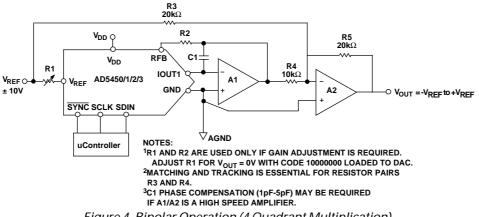


Figure 4. Bipolar Operation (4 Quadrant Multiplication)

Table II. Bipolar Code Table

Digital Input Analog Output (V)

1111 1111	+V _{REF} (127/128)	
1000 0000	0	
0000 0001	-V _{REF} (127/128)	
0000 0000	-V _{REF} (128/128)	

Stability

In the I-to-V configuration, the I_{OUT} of the DAC and the inverting node of the op amp must be connected as close as possible, and proper PCB layout techniques must be employed. Since every code change corresponds to a step function, gain peaking may occur if the op amp has limited GBP and there is excessive parasitic capacitance at the inverting node. This parasitic capacitance introduces a pole into the open loop response which can cause ringing or instability in the closed loop applications circuit.

An optional compensation capacitor, C1 can be added in parallel with R_{FB} for stability as shown in figures 3 and 4. Too small a value of C1 can produce ringing at the output, while too large a value can adversely affect the settling time. C1 should be found empirically but 1-2pF is generally adequate for the compensation.

SINGLE SUPPLY APPLICATIONS

Voltage Switching Mode of Operation

Figure 5 shows these DACs operating in the voltageswitching mode. The reference voltage, V_{IN} is applied to the I_{OUT1} pin, I_{OUT2} is connected to AGND and the output voltage is available at the V_{REF} terminal. In this configuration, a positive reference voltage results in a positive output voltage making single supply operation possible. The output from the DAC is voltage at a constant impedance (the DAC ladder resistance). Thus an op-amp is necessary to buffer the output voltage. The reference input no longer sees a constant input impedance, but one that varies with code. So, the voltage input should be driven from a low impedance source.

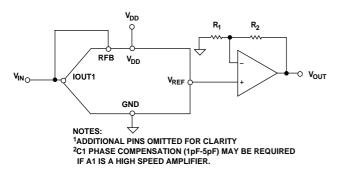


Figure 5. Single Supply Voltage Switching Mode Operation.

It is important to note that $V_{\rm IN}$ is limited to low voltages because the switches in the DAC ladder no longer have the same source-drain drive voltage. As a result their on resistance differs and this degrades the integral linearity of the DAC. Also, $V_{\rm IN}$ must not go negative by more than 0.3V or an internal diode will turn on, exceeding the max

AD5450/AD5451/AD5452/AD5453

ratings of the device. In this type of application, the full range of multiplying capability of the DAC is lost.

POSITIVE OUTPUT VOLTAGE

Note that the output voltage polarity is opposite to the V_{REF} polarity for dc reference voltages. In order to achieve a positive voltage output, an applied negative reference to the input of the DAC is preferred over the output inversion through an inverting amplifier because of the resistors tolerance errors. To generate a negative reference, the reference can be level shifted by an op amp such that the V_{OUT} and GND pins of the reference become the virtual ground and -2.5V respectively as shown in Figure 6.

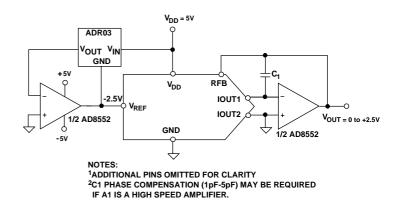


Figure 6. Positive Voltage output with minimum of components.

ADDING GAIN

In applications where the output voltage is required to be greater than V_{IN} , gain can be added with an additional external amplifier or it can also be achieved in a single stage. It is important to take into consideration the effect of temperature coefficients of the thin film resistors of the DAC. Simply placing a resistor in series with the RFB resistor will causing mis-matches in the Temperature coefficients resulting in larger gain temperature coefficient errors. Instead, the circuit of Figure 7 is a recommended method of increasing the gain of the circuit. R1, R2 and R3 should all have similar temperature coefficients, but they need not match the temperature coefficients of the DAC. This approach is recommended in circuits where gains of great than 1 are required.

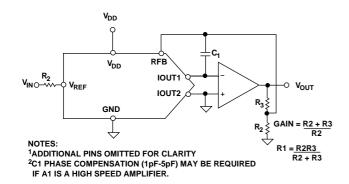


Figure 7. Increasing Gain of Current Output DAC

USED AS A DIVIDER OR PROGRAMMABLE GAIN ELEMENT

Current Steering DACs are very flexible and lend themselves to many different applications. If this type of DAC is connected as the feedback element of an op-amp and R_{FB} is used as the input resistor as shown in Figure 8, then the output voltage is inversely proportional to the digital input fraction D. For $D = 1-2^n$ the output voltage is

$$V_{OUT} = -V_{IN}/D = -V_{IN}/(1-2^{-n})$$

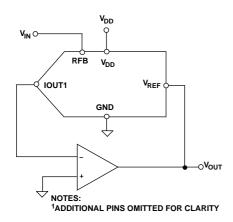


Figure 8. Current Steering DAC used as a divider or Programmable Gain Element

As D is reduced, the output voltage increases. For small values of the digital fraction D, it is important to ensure that the arnplifier does not saturate and also that the required accuracy is met. For example, an eight bit DAC driven with the binary code 10H (00010000), i.e., 16 decimal, in the circuit of Figure 8 should cause the output voltage to be sixteen times V_{IN} . However, if the DAC has a linearity specification of +/- 0.5LSB then D can in fact have the weight anywhere in the range 15.5/256 to 16.5/256 so that the possible output voltage will be in the range $15.5V_{IN}$ to $16.5V_{IN}$ —an error of + 3% even though the DAC itself has a maximum error of 0.2%.

DAC leakage current is also a potential error source in divider circuits. The leakage current must be counterbalanced by an opposite current supplied from the op amp through the DAC. Since only a fraction D of the current into the $V_{\rm REF}$ terminal is routed to the $I_{\rm OUT1}$ terminal, the output voltage has to change as follows:

Output Error Voltage Due to Dac Leakage

$$=$$
 (Leakage x R)/D

where R is the DAC resistance at the V_{REF} terminal. For a DAC leakage current of 10nA, R = 10 kilohm and a gain (i.e., 1/D) of 16 the error voltage is 1.6mV.

REFERENCE SELECTION

When selecting a reference for use with the AD5426 series of current output DACs, pay attention to the references output voltage temperature coefficient specification. This parameter not only affects the full scale error, but can also affect the linearity (INL and DNL) performance. The reference temperature coefficient should be consistent with the system accuracy specifications. For example, an 8-bit system required to hold its overall specification to within 1LSB over the temperature range 0-50°C dictates that the maximum system drift with temperature should be less than 78ppm/ºC. A 14-Bit system with the same temperature range to overall specification within 2LSBs requires a maximum drift of 10ppm/°C. By choosing a precision reference with low output temperature coefficient this error source can be minimized. Table IV. suggests some of the suitable dc references available from Analog Devices that are suitable for use with this range of current output DACs.

AMPLIFIER SELECTION

The primary requirement for the current-steering mode is an amplifier with low input bias currents and low input offset voltage. The input offset voltage of an op amp is multiplied by the variable gain (due to the code dependent output resistance of the DAC) of the circuit. A change in this noise gain between two adjacent digital fractions produces a step change in the output voltage due to the amplifier's input offset voltage. This output voltage change is superimposed upon the desired change in output between the two codes and gives rise to a differential linearity error, which if large enough could cause the DAC to be non-monotonic.

The input bias current of an op amp also generates an offset at the voltage output as a result of the bias current flowing in the feedback resistor R_{FB} . Most op amps have input bias currents low enough to prevent any significant errors in 12-Bit applications, however for 14-Bit applications some consideration should be given to selecting an appropriate amplifier.

Common mode rejection of the op amp is important in voltage switching circuits, since it produces a code dependent error at the voltage output of the circuit. Most op amps have adequate common mode rejection for use at 8-, 10- and 12-Bit resolution.

Provided the DAC switches are driven from true wideband low impedance sources (V_{IN} and AGND) they settle quickly. Consequently, the slew rate and settling time of a voltage switching DAC circuit is determined largely by the output op amp. To obtain minimum settling time in this configuration, it is important to minimize capacitance

Table IV. Listing of suitable ADI Precision References recommended for use with AD5450/1/2/3 DACs.

Reference	Output Voltage	Initial Tolerance	Temperature Drift	0.1Hz to 10Hz noise	Package
ADR01	10 V	0.1%	3ppm/°C	20µVp-p	SC70, TSOT, SOIC
ADR02	5 V	0.1%	3ppm/°C	10µVp-p	SC70, TSOT, SOIC
ADR03	2.5 V	0.2%	3ppm/°C	10µVp-p	SC70, TSOT, SOIC
ADR425	5 V	0.04%	3ppm/°C	3.4µVp-p	MSOP, SOIC

Table V. Listing of some precision ADI Op Amps suitable for use with AD5450/1/2/3 DACs.

Part #	Max Supply Voltage V	V _{os} (max)µV	VI _B (max) nA	GBP MHz	Slew Rate V/µs	t _{SETTLE} with AD5453
OP97	± 20	25	0.1	0.9	0.2	
OP1177	± 18	60	2	1.3	0.7	
AD8551	± 6	5	0.05	1.5	0.4	

Part #	Max Supply Voltage V	BW @ A _{CL} MHz	Slew Rate V/µs	t _{SETTLE} with AD5453	V _{OS} (max)µV	I _B (max) nA
AD8065	± 12	145	180		1500	0.01
AD8021	± 12	200	100		1000	1000
AD8038	±5	350	425		3000	0.75
AD9631	± 5	320	1300		10000	7000

at the V_{REF} node (voltage output node in this application) of the DAC. This is done by using low inputs capacitance buffer amplifiers and careful board design.

Most single supply circuits include ground as part of the analog signal range, which in turns requires an ampliferthat can handle rail to rail signals, there is a large range of single supply amplifiers available from Analog Devices.

PCB LAYOUT AND POWER SUPPLY DECOUPLING

In any circuit where accuracy is important, careful consideration of the power supply and ground return layout helps to ensure the rated performance. The printed circuit board on which the AD5426/AD5432/AD5443 is mounted should be designed so that the analog and digital sections are separated, and cofined to certain areas of the board. If the DAC is in a system where multiple devices require an AGND-to-DGND connection, the connection should be made at one point only. The star ground point should be established as close as possible to the device.

These DACs should have ample supply bypassing of 10 μ F in parallel with 0.1 μ F on the supply located as close to the package as possible, ideally right up against the device. The 0.1 μ F capacitor should have low Effective Series Resistance (ESR) and Effective Series Inductance (ESI), like the common ceramic types that provide a low impedance path to ground at high frequencies, to handle transient currents due to internal logic switching. Low ESR 1 μ F to 10 μ F tantalum or electrolytic capacitors should also be applied at the supplies to minimize transient disturbance and filter out low frequency ripple.

Fast switching signals such as clocks should be shielded with digital ground to avoid radiating noise to other parts of the board, and should never be run near the reference inputs. Avoid crossover of digital and analog signals. Traces on opposite sides of the board should run at right angles to each other. This reduces the effects of feedthrough through the board. A microstrip technique is by far the best, but not always possible with a doublesided board. In this technique, the component side of the board is dedicated to ground plane while signal traces are placed on the solder side.

It is good practice to employ compact, minimum lead length PCB layout design. Leads to the input should be as short as possible to minimize IR drops and stray inductance.

The PCB metal traces between V_{REF} and R_{FB} should also be matched to minimize gain error. To maximize on high

frequency performance, the I-to-V amplifier should be located as close to the device as possible.

Part #	Resolution	#DACs	INL	ts	Interface	Package	Features
AD5403 ¹	8	2	±0.25	20ns	Parallel	CP-40	10 MHz BW, 17 ns CS Pulse Width, 4-
	-						Quadrant Multiplying Resistors
AD5410 ¹	8	1	±0.25	20ns	Serial	RU-16	10 MHz BW, 50 MHz Serial, 4- Quadrant
							Multiplying Resistors
AD5413 ¹	8	2	±0.25	20ns	Serial	RU-24	10 MHz BW, 50 MHz Serial, 4- Quadrant
							Multiplying Resistors
AD5424	8	1	±0.25	60ns	Parallel	RU-16, CP-20	10 MHz BW, 17 ns CS Pulse Width
AD5425	8	1	±0.25	100ns	Serial	RM-10	Byte Load,10 MHz BW, 50 MHz Serial
AD5426	8	1	±0.25	100ns	Serial	RM-10	10 MHz BW, 50 MHz Serial
AD5428 ²	8	2	±0.25	60ns	Parallel	RU-20	10 MHz BW, 17 ns CS Pulse Width
AD5429 ²	8	2	±0.25	100ns	Serial	RU-10	10 MHz BW, 50 MHz Serial
$AD5450^2$	8	1	±0.25	100ns	Serial	RJ-8	10 MHz BW, 50 MHz Serial
AD5404 ¹	10	2	± 0.5	25ns	Parallel	CP-40	10 MHz BW, 17 ns CS Pulse Width, 4-
							Quadrant Multiplying Resistors
AD5411 ¹	10	1	± 0.5	25ns	Serial	RU-16	10 MHz BW, 50 MHz Serial, 4- Quadrant
							Multiplying Resistors
$AD5414^{1}$	10	2	± 0.5	25ns	Serial	RU-24	10 MHz BW, 50 MHz Serial, 4- Quadrant
							Multiplying Resistors
AD5432	10	1	± 0.5	110ns	Serial	RM-10	10 MHz BW, 50 MHz Serial
AD5433	10	1	± 0.5	70ns	Parallel	RU-20, CP-20	
AD5439 ²	10	2	± 0.5	110ns	Serial	RU-16	10 MHz BW, 50 MHz Serial
AD5440 ²	10	2	±0.5	70ns	Parallel	RU-24	10 MHz BW, 17 ns CS Pulse Width
AD5451 ²	10	1	±0.25	110ns	Serial	RJ-8	10 MHz BW, 50 MHz Serial
AD5405 ²	12	2	± 1	120ns	Parallel	CP-40	10 MHz BW, 17 ns CS Pulse Width, 4-
1.5.4.4.01					a		Quadrant Multiplying Resistors
AD5412 ¹	12	1	±1	160ns	Serial	RU-16	10 MHz BW, 50 MHz Serial, 4- Quadrant
1	1.0			4.0.0	a	DII 04	Multiplying Resistors
AD5415 ²	12	2	±1	160ns	Serial	RU-24	10 MHz BW, 50 MHz Serial, 4- Quadrant
1.5.5.1.10	1.0			4.0.0	a	D1 ()	Multiplying Resistors
AD5443	12	1	± 1	160ns	Serial	RM-10	10 MHz BW, 50 MHz Serial
AD5445	12	1	±1	120ns	Parallel	RU-20, CP-20	
$AD5447^{2}$	12	2	±1	120ns	Parallel	RU-24	10 MHz BW, 17 ns <i>CS</i> Pulse Width
$AD5449^{2}$	12	2	± 1	160ns	Serial	RU-16	10 MHz BW, 50 MHz Serial
$AD5452^{2}$	12	1	± 0.5	160ns	Serial	RJ-8, RM-8	10 MHz BW, 50 MHz Serial
AD5453 ²	14	1	±2	180ns	Serial	RJ-8, RM-8	10 MHz BW, 50 MHz Serial

Overview of AD54xx devices

¹Future parts, contact factory for availability ²In development, contact factory for availability

OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

8 Lead TSOT (UJ-8)

